




<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10750908</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>PINCU ET AL.</p>
	<p>Examiner</p> <p>Kaplan, Hal I</p>	<p>Art Unit</p> <p>2836</p>

Class	SubClass	Date	Examiner
700	286,291,297	08/14/2006	HK

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<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10750908	PINCU ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Notes	Date	Examiner
361/58,62,103,104 (consulted Stephen W. Jackson)	06/15/2006	HK
700/286,291,297 (consulted Jayprakash Gandhi and Albert Paladini)	06/15/2006	HK
EAST (US-PGPUB,USPAT,USOCR,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	08/14/2006	HK
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<b>Interference Searched</b>  	Application/Control No.  10750908	Applicant(s)/Patent Under Reexamination  PINCU ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

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